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INSTRUMENTATION AND MEASUREMENT SOCIETY NEWSLETTER

December 2015

In this issue

- I&M Conference Calendar
- I&M Conference Call for Papers
- Technical Communities
- 2016 Award Nominations
- 2016 Officers

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IEEE Instrumentation & Measurement Magazine

The latest issue of [IEEE Instrumentation & Measurement Magazine](#) is in the mail and is retrievable now from IEEE Xplore, the IEEE online digital library.

About the IEEE Instrumentation & Measurement Society Newsletter

Engineers today start their careers with excellent technical skills and subject matter expertise. The IEEE Instrumentation & Measurement (I&M;) Newsletter includes time sensitive news useful to its members and highlights content of the current issue of *IEEE Instrumentation & Measurement Magazine*.



I&M Conference Calendar

We hold numerous workshops throughout the year. Please refer to the I&M; [Conference website](#) for a full listing. For more information on any of the conferences, please contact [Alessandra Flammini](#), VP of Conferences for the I&M; Society.



The 2016 [IEEE Sensors Applications Symposium](#) (SAS) will be held in Catania, Italy 20-22 April 2016. IEEE Sensors Applications Symposium is a unique opportunity for researchers and developers working in the field of sensors and their applications. General and special sessions will be dedicated to sharing experience and knowledge in the field of sensor technologies, sensing methodologies and applications for sensors as well as the role and the use of sensors in strategic fields ranging from environment monitoring to ambient assisted living. To register, visit our [website](#).


All *IEEE Instrumentation & Measurement Magazine* subscribers can access the online edition using their [IEEE Account](#).

 [Image of August 2015 IEEE I&M Magazine](#)

Feature articles in this issue include:

- "The pillars of metrology"
- "Traceable calibrations of Rogowski coils at high AC currents"
- "The story of the right measurement that caused injustice and the wrong measurement that did justice; How to explain the importance of metrology to lawyers and judges [Legal Metrology]"
- "Camera calibration and pose estimation from planes"
- "A new approach to the kelvin [Basic Metrology]"
- "Calibration of low-cost triaxial inertial sensors"
- "Uncertainty: Words on the loose [Future Trends in I&M;]"
- "Volunteer [Life After Graduation]"
- "Traceable measurements of electrical impedance"
- "Drilling fluid processing: preparation, maintenance and continuous conditioning"

IEEE Fellow

 Congratulations to Mark Yeary, I&M; member, who was elevated to IEEE Fellow in 2016.

His citation is "for contributions to radar systems for meteorology."

I&M; Strategic Planning Meeting

The I&M; Officers and Editors will be hosting the next Strategic Planning Meeting in Atlanta, GA 18-20 February 2016.

IEEE Senior Membership

2016 IEEE International Instrumentation and Measurement Technology Conference

MAY 23-26, 2016 | Taipei International Convention Center | Taipei, Taiwan

The 2016 [IEEE International Instrumentation and Measurement Technology Conference](#) (I2MTC) will be held in Taipei, Taiwan 23-26 May 2016. For registration information, please visit our [website](#).



I&M; Sponsored Conferences Currently Soliciting Paper Submissions

2016 IEEE International Symposium on
MeMeA | Medical Measurements and Applications
May 12-14, 2016 | Benevento, Italy

The 2016 [IEEE International Symposium on Medical Measurements and Applications](#) (MeMeA) will be held in Benevento, Italy 12-14 May 2016. [View the Call for Papers](#). Paper submission deadline is 10 January 2016.

I&M; Technically Co-Sponsored Conferences



The [2016 IEEE First International Conference on Control, Measurement and Instrumentation](#) (CMI) will be held 8-10 January 2016 at Kolkata, India.



The 3rd IEEE International Workshop on Metrology for AeroSpace will be held in Florence, Italy 22-23 June 2016. Following the success of the first two editions of [IEEE International Workshop on Metrology for Aerospace](#) (MetroAeroSpace), it was considered convenient to promote a third edition of this event, which aims at reinforcing and supporting the collaborations among people working in developing instrumentation and measurement methods for aerospace. This new edition will keep pursuing the state of the art and practice started over the past years. Attention is paid, but not limited to, new technology for metrology-assisted production in aerospace industry, aircraft component measurement, sensors and associated signal conditioning for aerospace, and calibration methods for electronic test and measurement for aerospace. Find information on the call for papers here. The submission date is 22 January 2016.

Have a conference you'd like advertised in the I&M; Society Newsletter? Contact [Lauren](#)

IEEE Senior Membership is the highest grade for which application may be made and requires experience reflecting professional maturity. Candidates need to be an engineer, scientist, educator, technical executive, or originator in IEEE-designated fields in professional practice for at least ten years and shall have shown significant performance over a period of at least five of those years.

An [application for Senior Membership](#) requires three references unless nominated by a Senior member, and in that case requires two references.

Congratulations to the newly-elected I&M Senior members for 2015 thus far: Eduardo Cano, Paul Erickson, Joseph Kaiser, Chetan Kulkarni, Iman Morsi, Tom Nelson, Jomar Ochoco, Jose Pelegri Sebastia, Lihui Peng, Arash Samani, Sarah Seguin, Janusz Smulko, Jesus Urena, Ramli Adnan, Ioannis Gonos, James Henry, Barry Male, Carlo Muscas, Viviana Vladutescu, Detlef Pape, Herve Saint-Jalmes, Jeffrey Miller, Marc Bossche, Ilena Baran, Dwight Clayton, Juan Anzurez-Marin, Robert Atkinson, Niranjana Debnath, Christopher Eio, Martin Hudlicka, Stephen Uurtamo, Marco Jose Da Silva, Pete Gregory, Mahesh Nair, Andrew Scott and Chao Tan.

[Stockman](#) for details on how to have it included.



Technical Committees

I&M; has many different Technical Committees (TC). Our TCs define and implement the technical directions of the Society. As a fundamental element of the Society all members are invited - and encouraged - to participate in one or more of its technical committees. Please contact Jorge Daher, VP Technical and Standards Activities, at j.daher@ieee.org or any member of the Technical and Standards Activities Committee, if you are interested in membership in one or more of our TCs. To view the complete list of TCs, visit our [website](#).



Award Nominations

Faculty Course Development Award

The Faculty Course Development Award is to support and encourage faculty members to develop a new course or significantly revise an existing course with specific focus on Instrumentation and/or Measurement, taught in an accredited (in accordance to the accepted rules of the country of applicant) engineering, physics, or science curriculum. Presentation will be made at the Awards Luncheon at the IEEE International Instrumentation and Measurement Technology Conference (I2MTC). Nominations are due by **1 February 2016**.

To nominate, please [visit our website](#).

Graduate Fellowship Award

The purpose of the grant is to support and encourage graduate-level research in the area of instrumentation and measurement. Nominations are due by **1 February 2016**.

To nominate, please [visit our website](#).

2017 IEEE Joseph F. Keithley Award in Instrumentation & Measurement

The IEEE Joseph F. Keithley Award in Instrumentation & Measurement is presented for outstanding contributions in electrical measurements. It was established in 2001 and was presented for the first time in 2004. Nominations for the 2017 IEEE awards cycle are currently being solicited and the deadline is **31 January 2016**. For more information, please refer to the [website](#).

To nominate, please [visit our website](#).



Attention Book Authors

Advertise your book on the I&M; website! The Instrumentation & Measurement Society provides a list of book titles written by IMS authors on the I&M; [website](#). The Society believes that books are an excellent avenue to disseminate the most advanced state-of-the-art within and outside of the community and that the website will help to spread the good news about the hard work of the authors. The guidance here govern which titles will be displayed. We look forward to your contributions! Visit our [website](#) for terms and guidelines.



2016 Officer Election Results

The I&M; Society AdCom held its Fall 2015 meeting in Lisbon, Portugal 15-17 October 2015. Officer elections were held and the following candidates were elected for the upcoming term:



Ruth Dyer
President



Max Cortner
Executive Vice President



Mark Yeary
VP Conferences



Salvatore Baglio
VP Education



Dario Petri
VP Finance



Shervin Shirmohammadi
VP Membership



Zheng Liu
VP Publications



Ruqiang Yan
VP Technical and Standards Activities (TSAC)



Juan Manuel Ramirez Cortes
Treasurer



Jorge S. Daher
Sr. Past President



Reza Zoughi
Jr. Past President

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